

HiPerFET™ Power MOSFETs

N-Channel Enhancement Mode
Avalanche Rated, Low Q_g
Low R_g , High dv/dt , Low t_{rr}

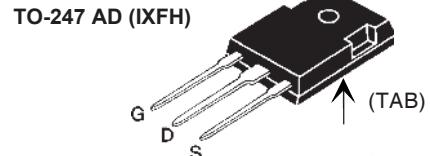
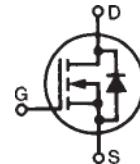
Preliminary Data Sheet

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	550		V
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$; $R_{GS} = 1 M\Omega$	550		V
V_{GS}	Continuous	± 30		V
V_{GSM}	Transient	± 40		V
I_{D25}	$T_c = 25^\circ C$	36		A
I_{DM}	$T_c = 25^\circ C$, pulse width limited by T_{JM}	144		A
I_{AR}	$T_c = 25^\circ C$	36		A
E_{AR}	$T_c = 25^\circ C$	50	mJ	
E_{AS}	$T_c = 25^\circ C$	2.5		J
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 A/\mu s$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 2 \Omega$	20	V/ns	
P_D	$T_c = 25^\circ C$	560		W
T_J		-55 ... +150		$^\circ C$
T_{JM}		150		$^\circ C$
T_{stg}		-55 ... +150		$^\circ C$
T_L	1.6 mm (0.063 in) from case for 10 s	300		$^\circ C$
M_d	Mounting torque	1.13/10 Nm/lb.in. 0.9/6 Nm/lb.in.		
Weight		6		g

IXFH36N55Q2

$$\begin{aligned}V_{DSS} &= 550 \text{ V} \\I_{D25} &= 36 \text{ A} \\R_{DS(on)} &= 0.18 \text{ } \Omega\end{aligned}$$

$$t_{rr} \leq 250 \text{ ns}$$



G = Gate

S = Source

TAB = Drain

Features

- Double metal process for low gate resistance
- International standard packages
- Epoxy meet UL 94 V-0, flammability classification
- Low $R_{DS(on)}$, low Q_g
- Avalanche energy and current rated
- Fast intrinsic rectifier

Applications

- DC-DC converters
- Switched-mode and resonant-mode power supplies, >500kHz switching
- DC choppers
- Pulse generation
- Laser drivers

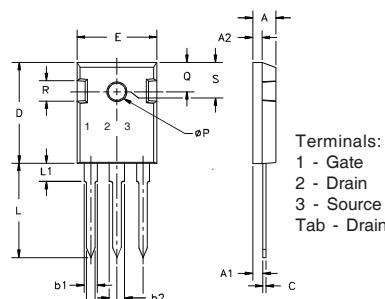
Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ C$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu A$	550		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4 \text{ mA}$	2.5		V
I_{GSS}	$V_{GS} = \pm 30 \text{ V}_{DC}$, $V_{DS} = 0$		± 100	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ C$ $T_J = 125^\circ C$	25 1	μA mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = 0.5 \cdot I_{D25}$ Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2 \%$		0.18	Ω

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = 0.5 \cdot I_{D25}$, pulse test	15	26	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	4100	pF	
		660	pF	
		160	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 2 \Omega$ (External),	17	ns	
		13	ns	
		42	ns	
		8	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	110	nC	
		23	nC	
		52	nC	
R_{thJC}		0.22	K/W	
R_{thCK}		0.25	K/W	

TO-247 AD (IXFH) Outline



Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	4.7	5.3	.185	.209
A ₁	2.2	2.54	.087	.102
A ₂	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b ₁	1.65	2.13	.065	.084
b ₂	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	.205	.225
L	19.81	20.32	.780	.800
L1		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	.232	.252
R	4.32	5.49	.170	.216
S	6.15	BSC	.242	BSC

Source-Drain Diode

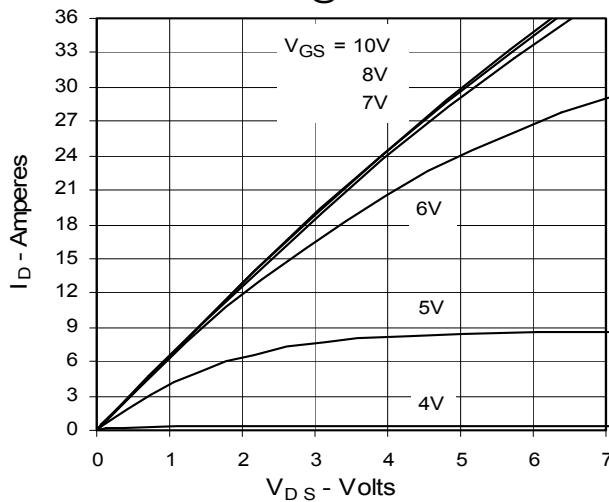
Characteristic Values
($T_J = 25^\circ\text{C}$, unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		36	A
I_{SM}	Repetitive; pulse width limited by T_{JM}		144	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = 25 \text{ A} \cdot di/dt = 100 \text{ A}/\mu\text{s}, V_R = 100 \text{ V}$	1 9	250 μC	ns A

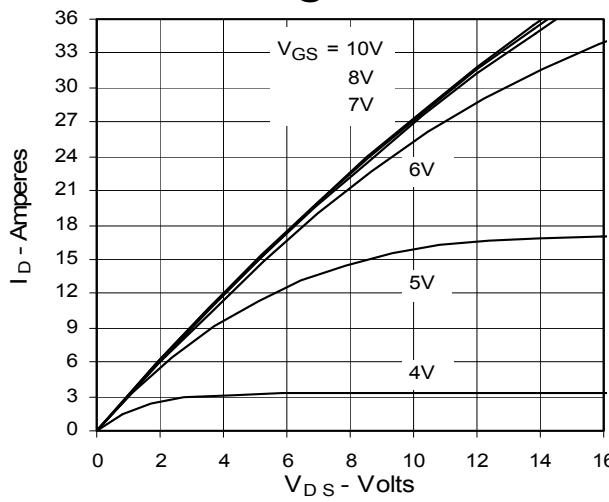
IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more
of the following U.S. patents: 4,850,072 4,931,844 5,034,796 5,063,307 5,237,481 5,381,025 6,404,065B1 6,162,665 6,534,343 6,583,505
4,835,592 4,881,106 5,017,508 5,049,961 5,187,117 5,486,715 6,306,728B1 6,259,123B1 6,306,728B1 6,683,344

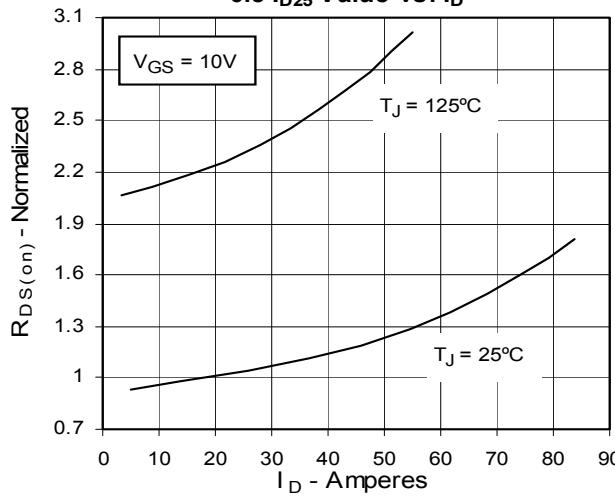
**Fig. 1. Output Characteristics
@ 25°C**



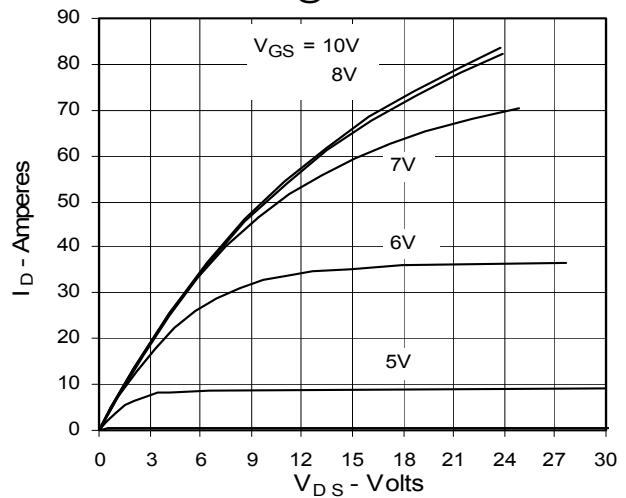
**Fig. 3. Output Characteristics
@ 125°C**



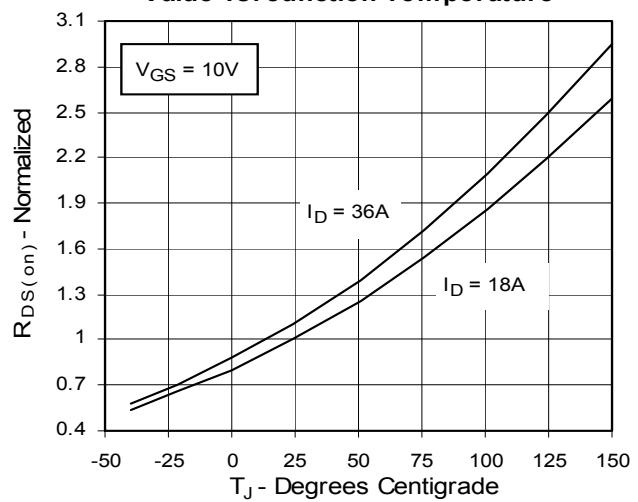
**Fig. 5. $R_{DS(on)}$ Normalized to
0.5 I_{D25} Value vs. I_D**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25}
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case
Temperature**

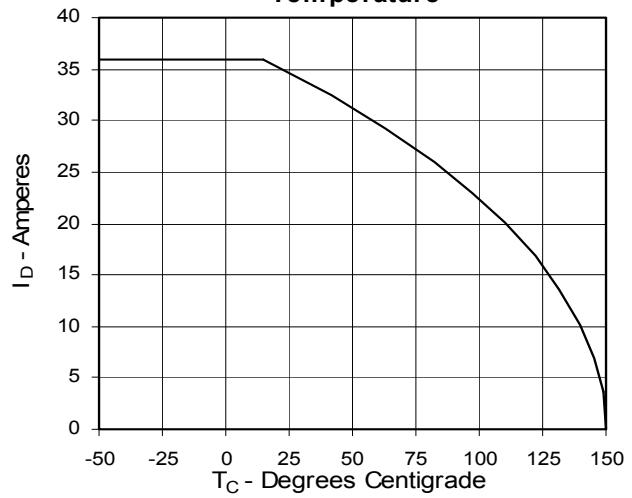


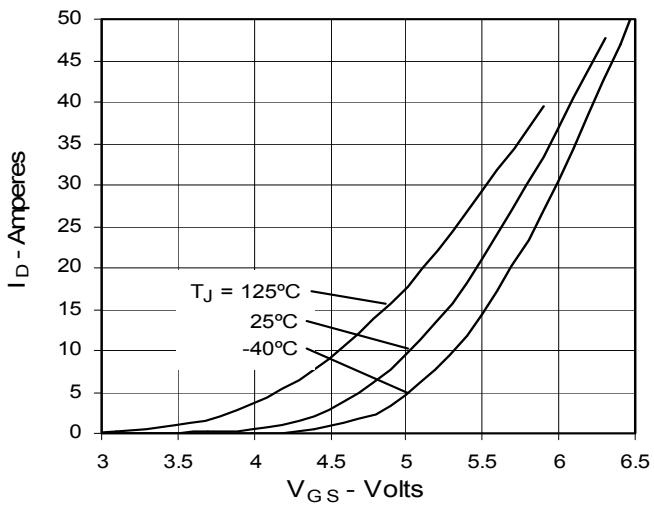
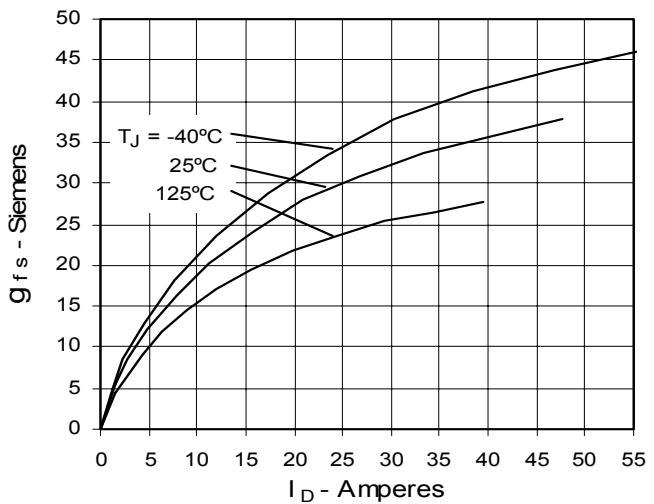
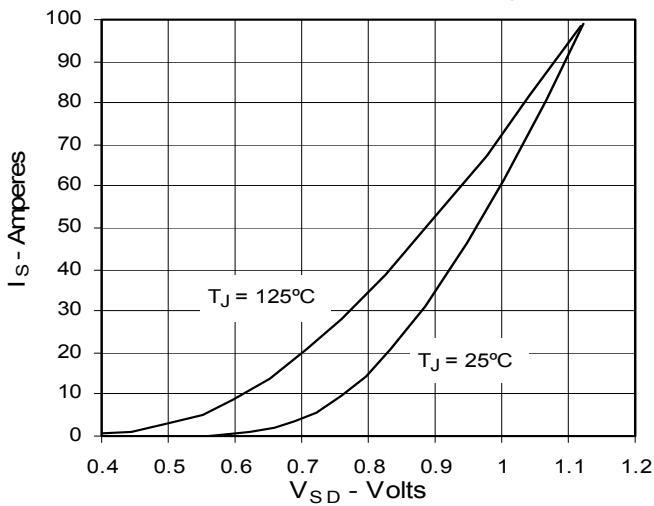
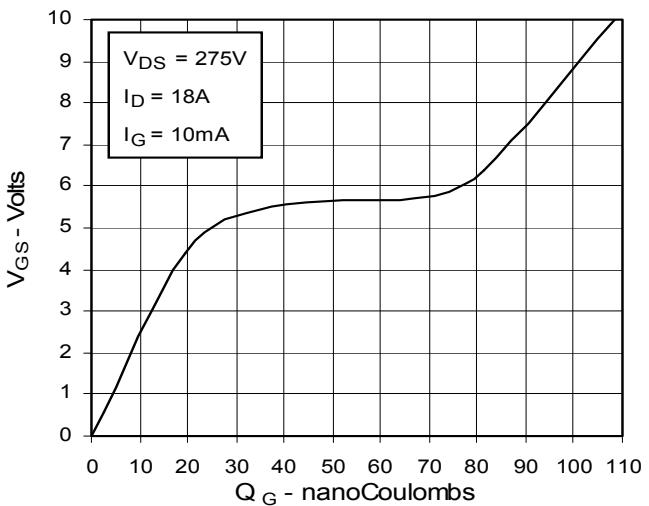
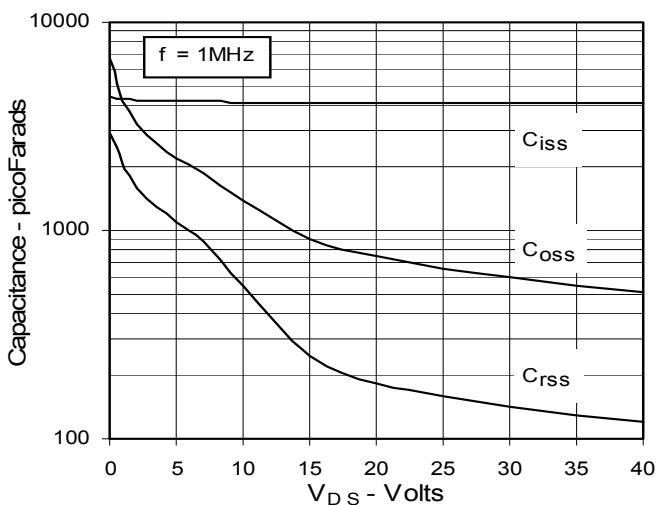
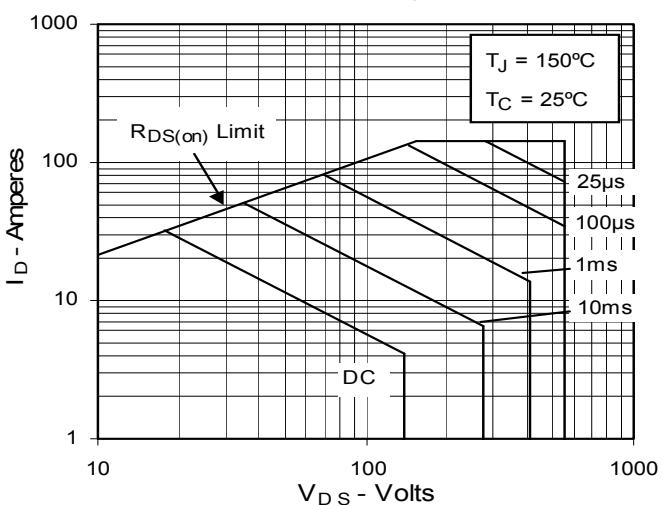
Fig. 7. Input Admittance

Fig. 8. Transconductance

Fig. 9. Source Current vs. Source-To-Drain Voltage

Fig. 10. Gate Charge

Fig. 11. Capacitance

Fig. 12. Forward-Bias Safe Operating Area


Fig. 13. Maximum Transient Thermal Resistance